A Rigorous Technique for Measuring the Scattering Matrix of a Multiport Device with a Two-Port Network Analyzer (Comments) (Mar. 1985 [T-MTT])

E. Van Lil. "A Rigorous Technique for Measuring the Scattering Matrix of a Multiport Device with a Two-Port Network Analyzer (Comments) (Mar. 1985 [T-MTT])." 1985 Transactions on Microwave Theory and Techniques 33.3 (Mar. 1985 [T-MTT]): 286-287.

In the above paper, Tippet and Speciale gave expressions for the correction to be made on the S matrix to account for the mismatches on the ports not connected to the network analyzer.

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